

ABSTRACT OF THE DISCLOSURE

Line segment extraction of a subject pattern is carried out based on an SEM image data DBL of a pattern to be subjected to evaluation, so as to obtain SEM line segment data DC. A superimposition displacement distance is then obtained based on CAD line segment data DD corresponding to the subject pattern and SEM line segment data DC, evaluation of a subject pattern is performed in two dimensions, and resulting evaluation value data DE is displayed graphically.